

MOSFETs Silicon P-Channel MOS (U-MOSVI)

# XSM6J372NW

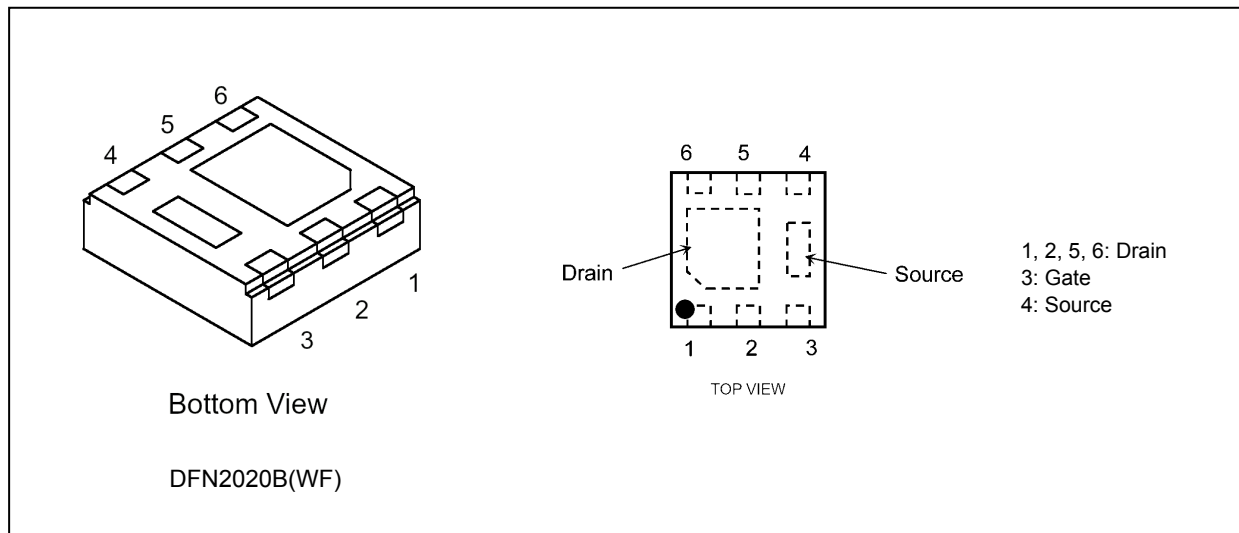
## 1. Applications

- Automotive
- Power Management Switches

## 2. Features

- (1) AEC-Q101 qualified
- (2) 1.8-V gate drive voltage.
- (3) Low drain-source on-resistance
  - $R_{DS(ON)} = 144 \text{ m}\Omega$  (max) (@ $V_{GS} = -1.8 \text{ V}$ )
  - $R_{DS(ON)} = 72.0 \text{ m}\Omega$  (max) (@ $V_{GS} = -2.5 \text{ V}$ )
  - $R_{DS(ON)} = 50.0 \text{ m}\Omega$  (max) (@ $V_{GS} = -4.5 \text{ V}$ )
  - $R_{DS(ON)} = 42.0 \text{ m}\Omega$  (max) (@ $V_{GS} = -10 \text{ V}$ )

## 3. Packaging and Pin Configuration



Start of commercial production  
2025-04

### 4. Absolute Maximum Ratings (Note) (Unless otherwise specified, $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Rating	Unit
Drain-source voltage	$V_{DSS}$	-30	V
Gate-source voltage	$V_{GSS}$	-12/+6	
Drain current (DC) (Note 1)	$I_D$	-6.0	A
Drain current (pulsed) ( $t \leq 10$ ms) (Note 1,2)	$I_{DP}$	-24.0	
Power dissipation (Note 3)	$P_D$	1.53	W
Power dissipation ( $t \leq 10$ s) (Note 3)	$P_D$	3.3	W
Single-pulse avalanche energy (Note 4)	$E_{AS}$	9.4	mJ
Single-pulse avalanche current	$I_{AS}$	-6.0	A
Channel temperature	$T_{ch}$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55 to 150	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Ensure that the channel temperature does not exceed  $150^\circ\text{C}$ .

Note 2: Pulse width (PW)  $\leq 10$  ms, duty  $\leq 1\%$

Note 3: Device mounted on an FR4 board. (25.4 mm  $\times$  25.4 mm  $\times$  1.6 mm, Cu Pad: 645 mm<sup>2</sup>)

Note 4:  $V_{DD} = -24$  V,  $T_{ch} = 25^\circ\text{C}$  (initial),  $L = 0.2$  mH,  $R_G = 25 \Omega$ ,  $I_{AS} = -6.0$  A

Note: This transistor is sensitive to electrostatic discharge and should be handled with care.

Note: The MOSFETs in this device are sensitive to electrostatic discharge. When handling this device, the worktables, operators, soldering irons and other objects should be protected against anti-static discharge.

Note: The channel-to-ambient thermal resistance,  $R_{th(ch-a)}$ , and the drain power dissipation,  $P_D$ , vary according to the board material, board area, board thickness and pad area. When using this device, be sure to take heat dissipation fully into account.

### 5. Thermal Characteristics

Characteristics	Symbol	Max	Unit
Channel-to-ambient thermal resistance (Note 1)	$R_{th(ch-a)}$	81.5	$^\circ\text{C}/\text{W}$

Note 1: Device mounted on an 25.4 mm  $\times$  25.4 mm  $\times$  1.6 mm FR4 glass epoxy board (Cu pad: 645 mm<sup>2</sup>)

### 6. Electrical Characteristics

#### 6.1. Static Characteristics ( $T_a = 25^\circ\text{C}$ unless otherwise specified)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current (Note 3)	$I_{GSS}$	$V_{GS} = -10/+6\text{ V}, V_{DS} = 0\text{ V}$	—	—	$\pm 1$	$\mu\text{A}$
Drain cut-off current (Note 3)	$I_{DSS}$	$V_{DS} = -30\text{ V}, V_{GS} = 0\text{ V}$	—	—	-1	
Drain-source breakdown voltage (Note 3)	$V_{(BR)DSS}$	$I_D = -10\text{ mA}, V_{GS} = 0\text{ V}$	-30	—	—	V
Drain-source breakdown voltage (Note 1),(Note 3)	$V_{(BR)DSX}$	$I_D = -10\text{ mA}, V_{GS} = 6\text{ V}$	-22	—	—	
Gate threshold voltage (Note 2),(Note 3)	$V_{th}$	$V_{DS} = -3\text{ V}, I_D = -1\text{ mA}$	-0.5	—	-1.2	
Drain-source on-resistance (Note 3)	$R_{DS(ON)}$	$I_D = -4.0\text{ A}, V_{GS} = -10\text{ V}$	—	36.0	42.0	$\text{m}\Omega$
		$I_D = -4.0\text{ A}, V_{GS} = -4.5\text{ V}$	—	42.5	50.0	
		$I_D = -2.5\text{ A}, V_{GS} = -2.5\text{ V}$	—	57.5	72.0	
		$I_D = -0.5\text{ A}, V_{GS} = -1.8\text{ V}$	—	76.5	144	

Note 1: If a reverse bias is applied between gate and source, this device enters  $V_{(BR)DSX}$  mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let  $V_{th}$  be the voltage applied between gate and source that causes the drain current ( $I_D$ ) to below (-1 mA for this device). Then, for normal switching operation,  $V_{GS(ON)}$  must be higher than  $V_{th}$ , and  $V_{GS(OFF)}$  must be lower than  $V_{th}$ . This relationship can be expressed as:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ .  
Take this into consideration when using the device.

Note 3: Pulse measurement.

#### 6.2. Dynamic Characteristics ( $T_a = 25^\circ\text{C}$ unless otherwise specified)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Input capacitance	$C_{iss}$	$V_{DS} = -15\text{ V}, V_{GS} = 0\text{ V},$ $f = 1\text{ MHz}$	—	560	—	$\text{pF}$
Reverse transfer capacitance	$C_{rss}$		—	65	—	
Output capacitance	$C_{oss}$		—	80	—	
Gate resistance	$r_g$		—	13.5	—	$\Omega$
Switching time (turn-on time)	$t_{on}$	See Fig. 6.2.1	—	15	—	ns
Switching time (turn-off time)	$t_{off}$		—	75	—	

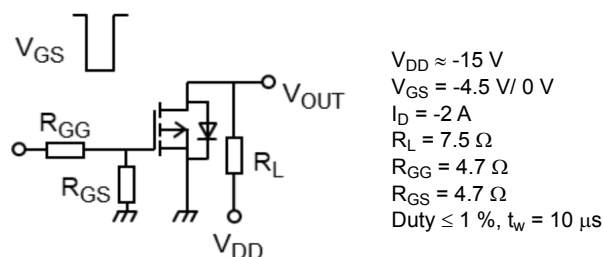


Fig. 6.2.1 Switching Time Test Circuit

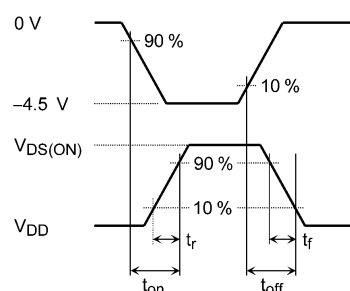


Fig. 6.2.2 Input Waveform/Output Waveform

### 6.3. Gate Charge Characteristics ( $T_a = 25^\circ\text{C}$ unless otherwise specified)

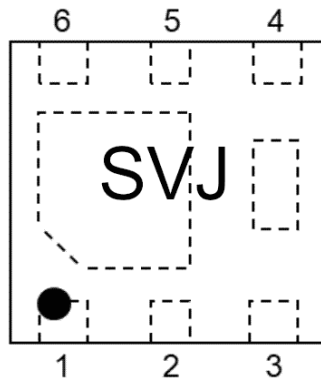
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Total gate charge (gate-source plus gate-drain)	$Q_g$	$V_{DD} = -15\text{ V}, V_{GS} = -4.5\text{ V},$ $I_D = -6.0\text{ A}$	—	8.2	—	nC
Gate-source charge 1	$Q_{gs1}$		—	1.1	—	
Gate-drain charge	$Q_{gd}$		—	2.2	—	

### 6.4. Source-Drain Characteristics ( $T_a = 25^\circ\text{C}$ unless otherwise specified)

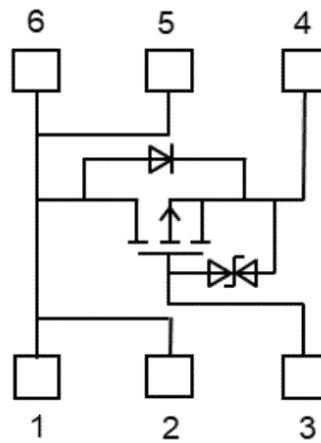
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Diode forward voltage (Note 1)	$V_{DSF}$	$I_{DR} = -6.0\text{ A}, V_{GS} = 0\text{ V}$	—	0.90	1.2	V

Note 1: Pulse measurement.

## 7. Marking



## 8. Internal Circuit



### 9. Characteristics Curves (Note)

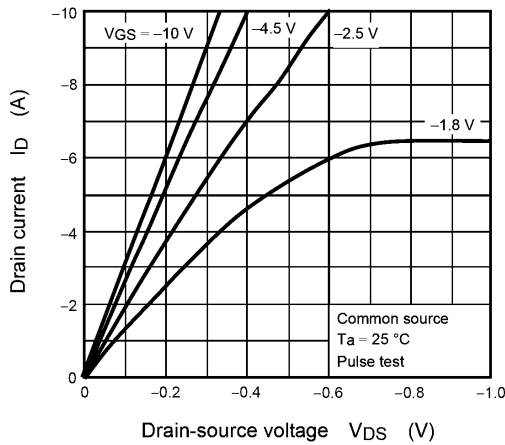


Fig. 9.1  $I_D - V_{DS}$

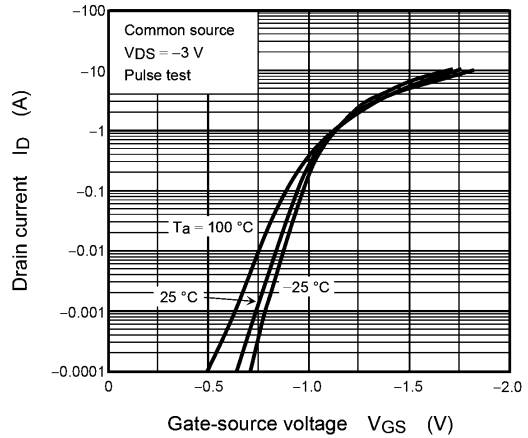


Fig. 9.2  $I_D - V_{GS}$

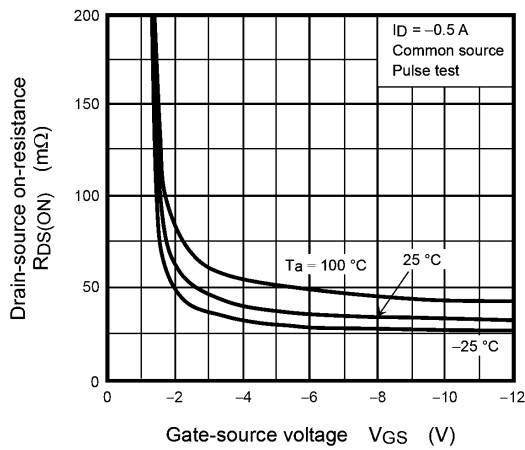


Fig. 9.3  $R_{DS(ON)} - V_{GS}$

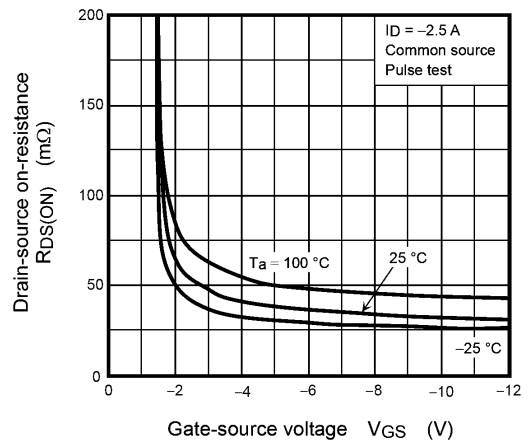


Fig. 9.4  $R_{DS(ON)} - V_{GS}$

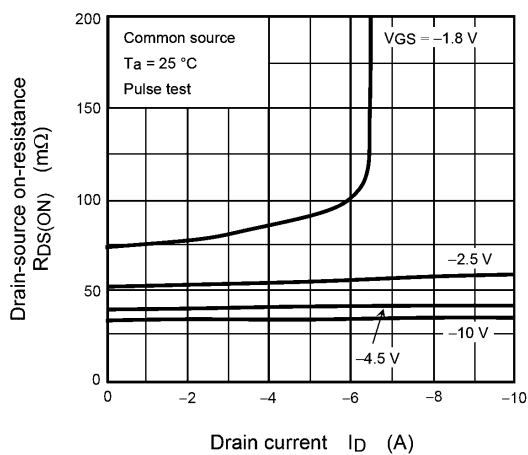


Fig. 9.5  $R_{DS(ON)} - I_D$

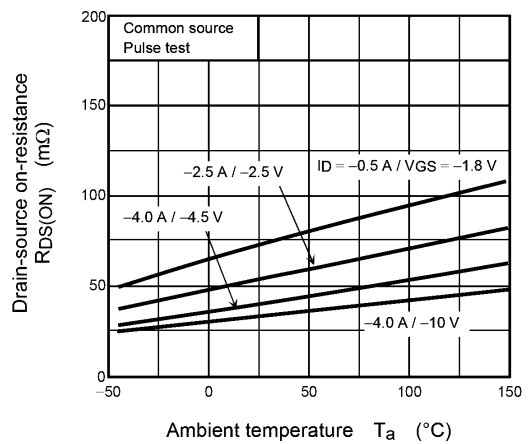
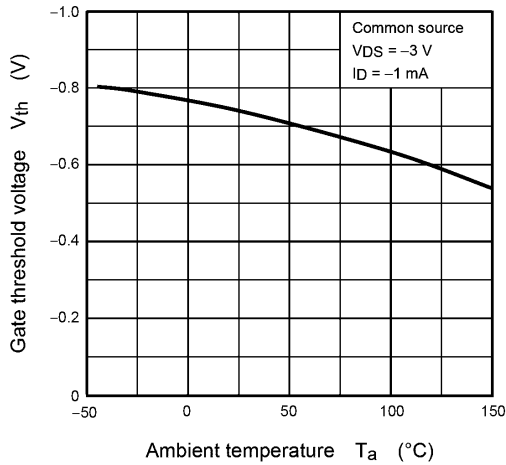
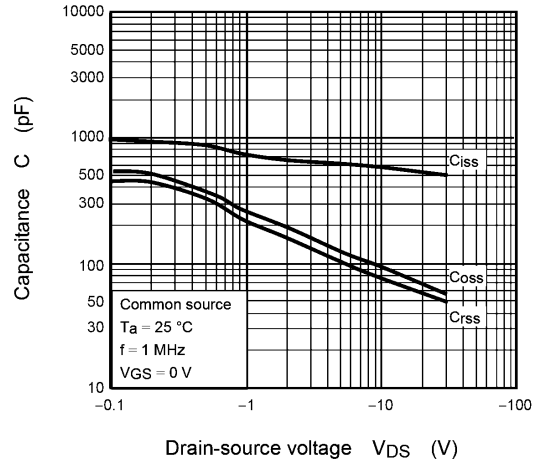


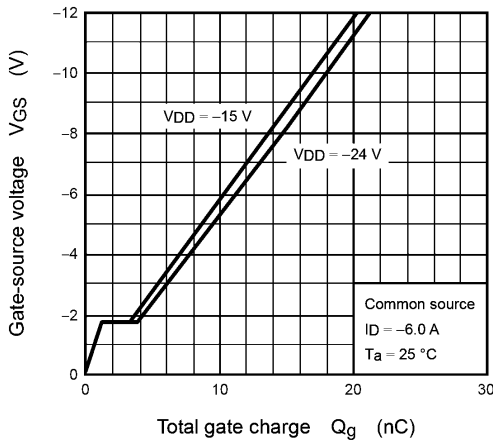
Fig. 9.6  $R_{DS(ON)} - T_a$



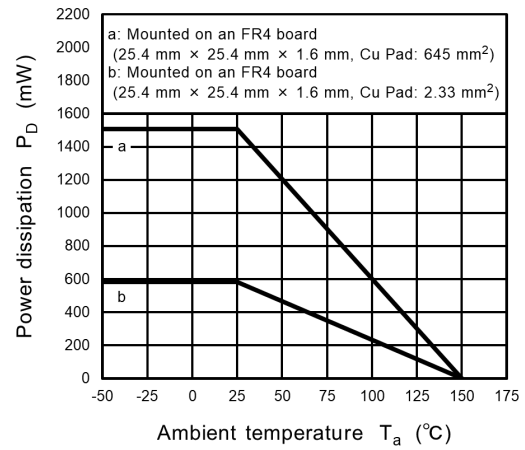
**Fig. 9.7  $V_{th} - T_a$**



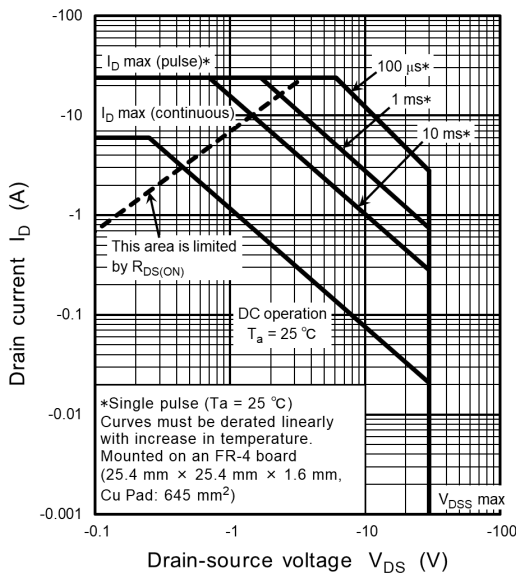
**Fig. 9.8  $C - V_{DS}$**



**Fig. 9.9 Dynamic Input Characteristics**



**Fig. 9.10  $P_D - T_a$**



**Fig. 9.11 Safe Operating Area**

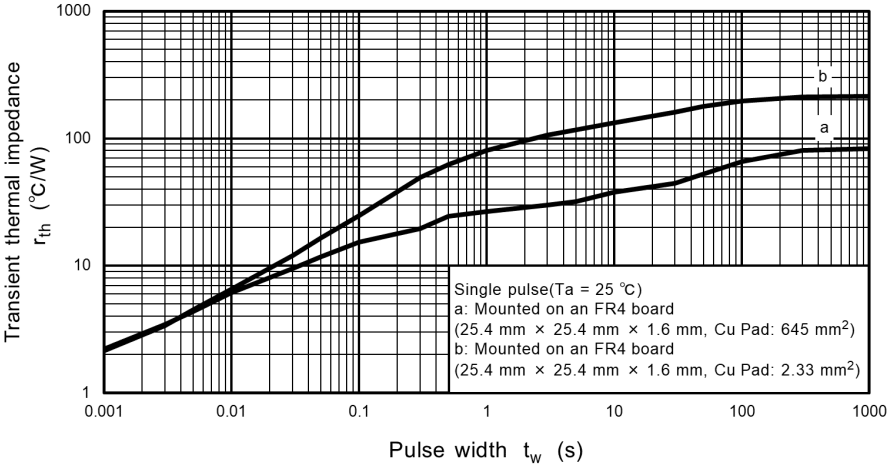


Fig. 9.12  $r_{th} - t_w$

Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



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